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1 Session P14: biomedical applications: Nonlinear virtual colon unfolding 96%



Anna Vilanova Bartrolí , Rainer Wegenkittl , Andreas König , Eduard Gröller

Proceedings of the conference on Visualization '01 October 2001

The majority of virtual endoscopy techniques tries to simulate a real endoscopy. A real endoscopy does not always give the optimal information due to the physical limitations it is subject to. In this paper, we deal with the unfolding of the surface of the colon as a possible visualization technique for diagnosis and polyp detection. A new two-step technique is presented which deals with the problems of double appearance of polyps and nonuniform sampling that other colon unfolding techniques suf ...

2 Session 13: audio processing and retrieval: Speaker change detection 77%
and tracking in real-time news broadcasting analysis



Lie Lu , Hong-Jiang Zhang

Proceedings of the tenth ACM international conference on Multimedia December 2002

This paper addresses the problem of real time speaker change detection and speaker tracking in broadcasted news video analysis. In such a case, both speaker identities and number of speakers are assumed unknown. A two-step speaker change detection algorithm, including potential change detection and refinement, is proposed. Speaker tracking is performed based on the results of speaker change detection. A Bayesian Fusion method is used to fuse multiple audio features to get a more reliable result. ...

3 Virtual voyage: interactive navigation in the human colon 77%



Lichan Hong , Shigeru Muraki , Arie Kaufman , Dirk Bartz , Taosong He

Proceedings of the 24th annual conference on Computer graphics and interactive techniques August 1997

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1 Image snapping 84%



Michael Gleicher

Proceedings of the 22nd annual conference on Computer graphics and interactive techniques September 1995

2 Skeletal/medial axis representations: Efficient computation of a 77%



simplified medial axis

Mark Foskey , Ming C. Lin , Dinesh Manocha

Proceedings of the eighth ACM symposium on Solid modeling and applications
June 2003

Applications of the medial axis have been limited because of its instability and algebraic complexity. In this paper, we use a simplification of the medial axis, the θ -SMA, that is parameterized by a separation angle (θ) formed by the vectors connecting a point on the medial axis to the closest points on the boundary. We present a formal characterization of the degree of simplification of the θ -SMA as a function of θ , and we quantify the degree ...

3 Session P14: biomedical applications: Nonlinear virtual colon unfolding 77%



Anna Vilanova Bartrolí , Rainer Wegenkittl , Andreas König , Eduard Gröller

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The majority of virtual endoscopy techniques tries to simulate a real endoscopy. A real endoscopy does not always give the optimal information due to the physical limitations it is subject to. In this paper, we deal with the unfolding of the surface of the colon as a possible visualization technique for diagnosis and polyp detection. A new two-step technique is presented which deals with the problems of double appearance of polyps and nonuniform sampling that other colon unfolding techniques suffer from ...

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(distance image) <and> (downsaml* <or>
down-saml* <or> subsaml* <or>
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(distance <near/2> (map* <or> transform* <or> domain)) <and> (undersampl* <or> (under sampl*) <or> (sub sampl*) <or> (down sampl*))

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(distance transform*)

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(distance transform*) <and> (subpixel <or> (sub pixel) <or> subgrid <or> (sub grid))

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(distance transform*) <and> (accuracy)

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